

FIG. 1A
(PRIOR ART)

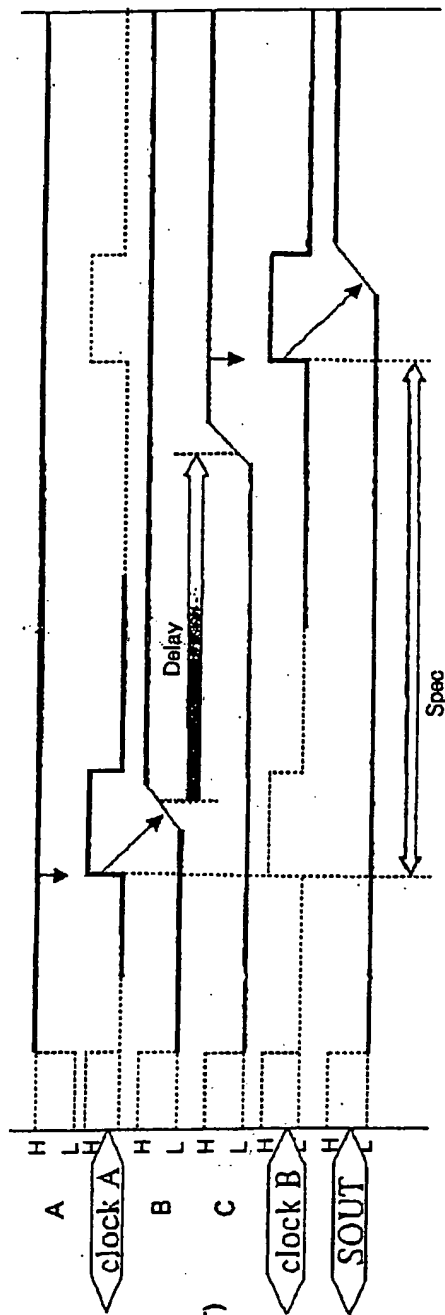
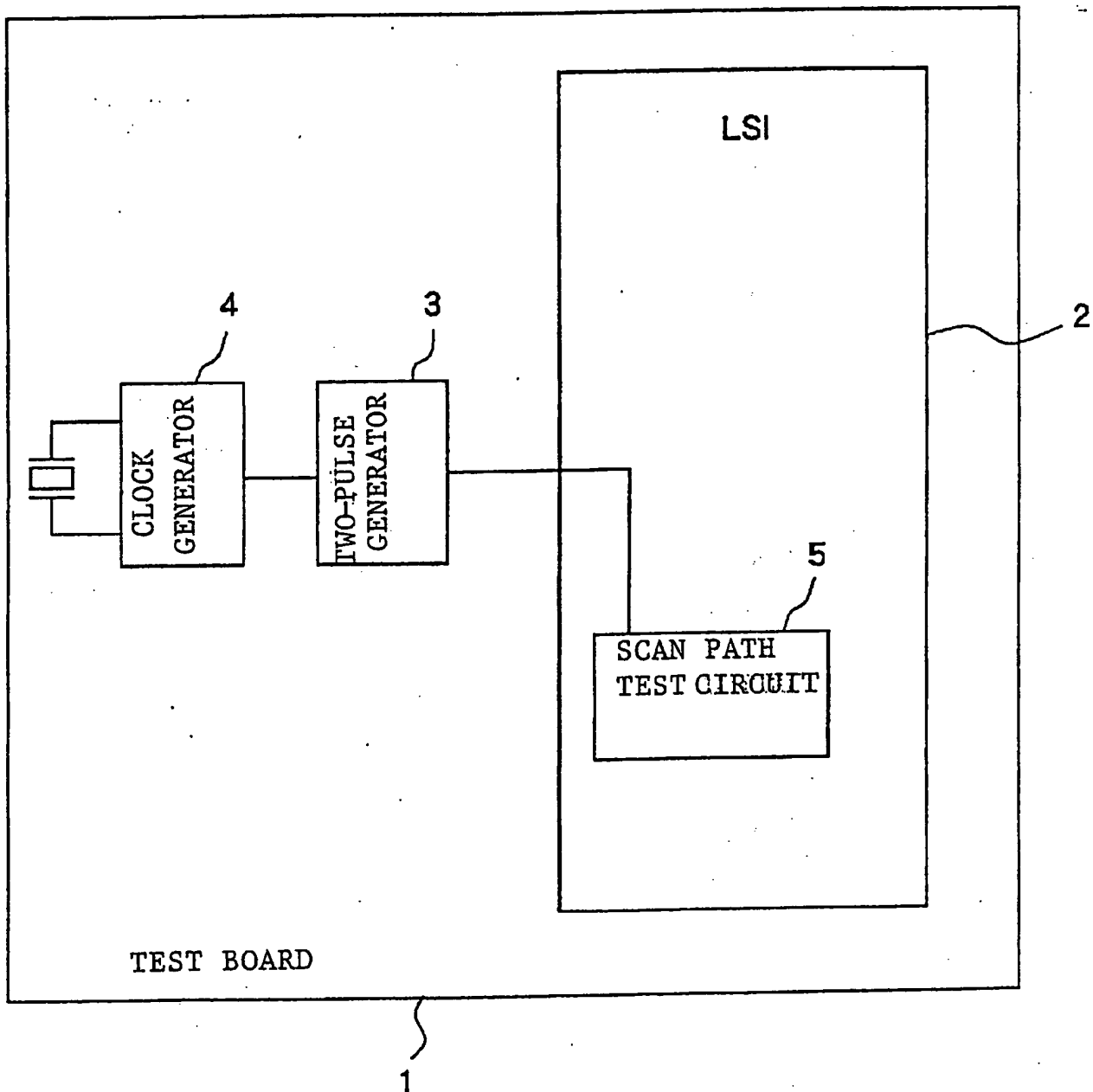


FIG. 1B
(PRIOR ART)

FIG. 2



SEMICONDUCTOR INTEGRATED
CIRCUIT DEVICE AND DEVICE
FOR TESTING SAME

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U.S. Serial No.: 10/063,472

Replacement Sheet

Sheet 3 of 8

FIG. 3

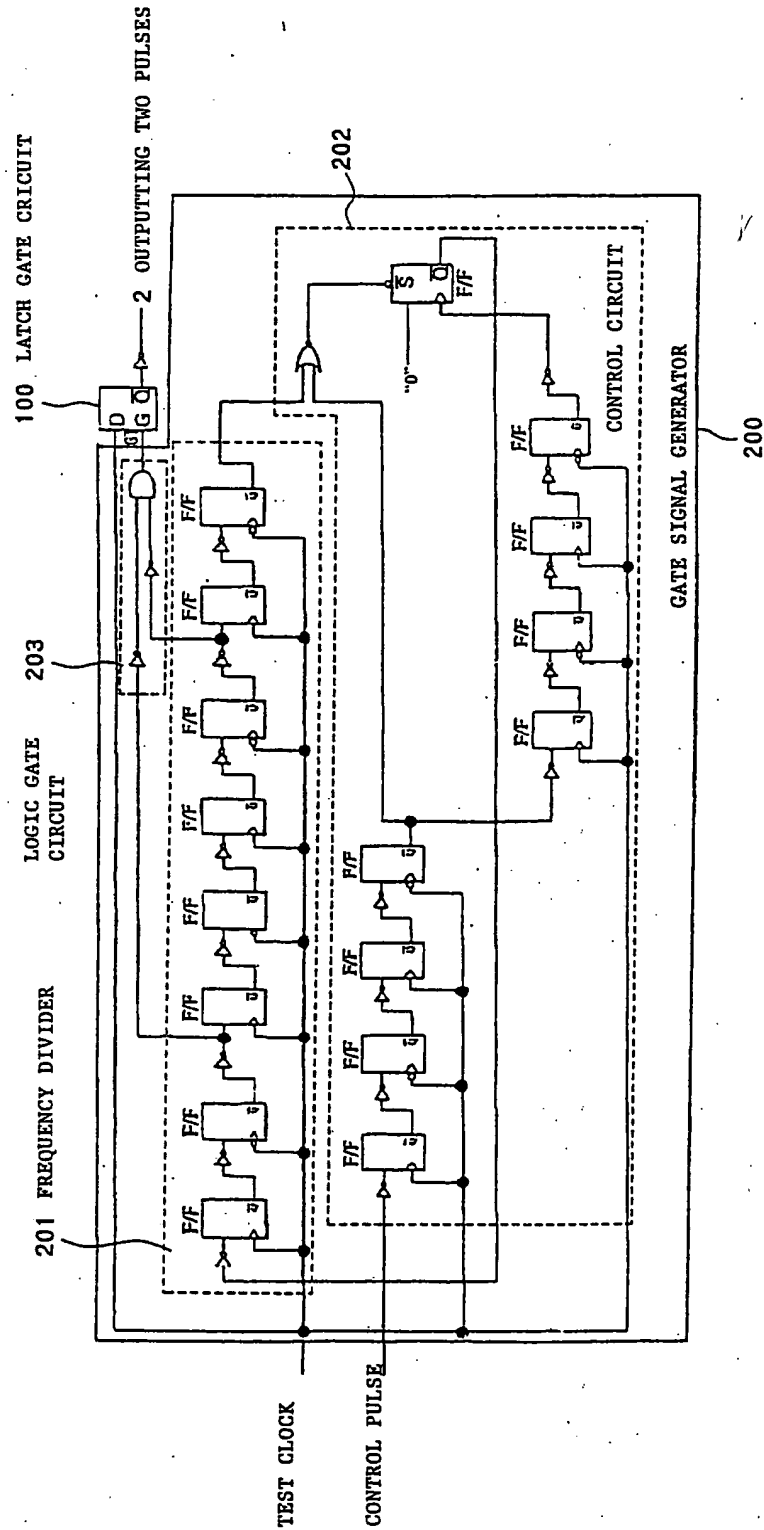
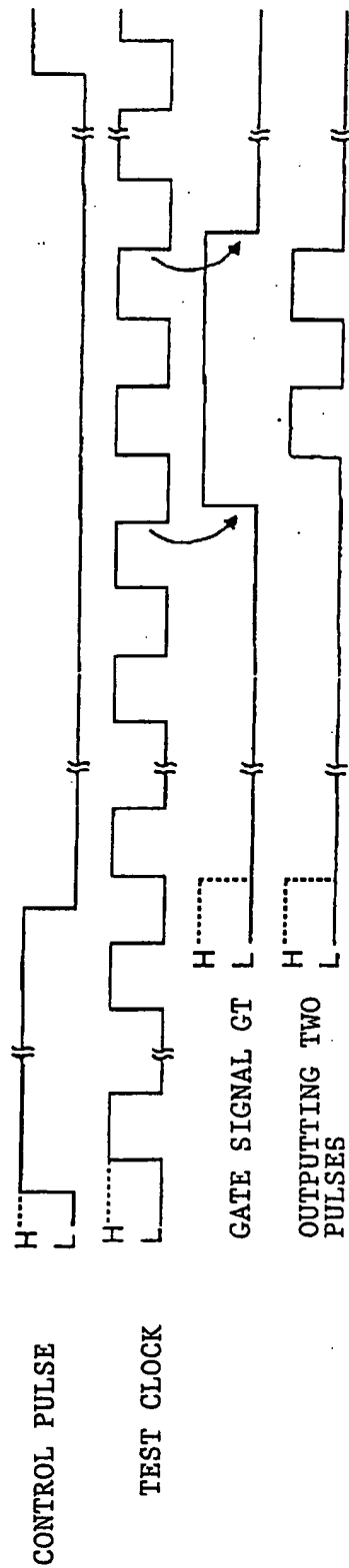


FIG. 4



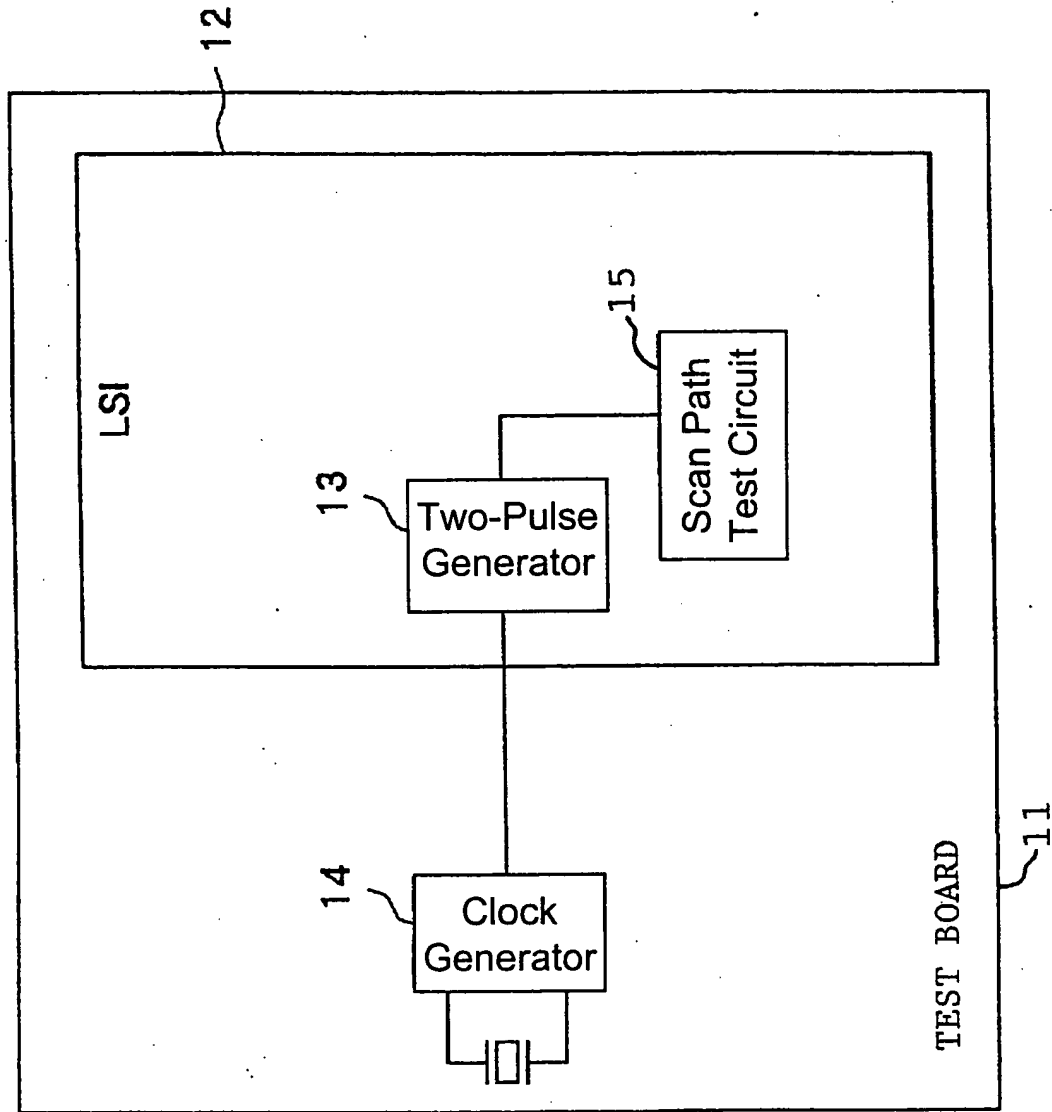


FIG. 5

FIG. 6

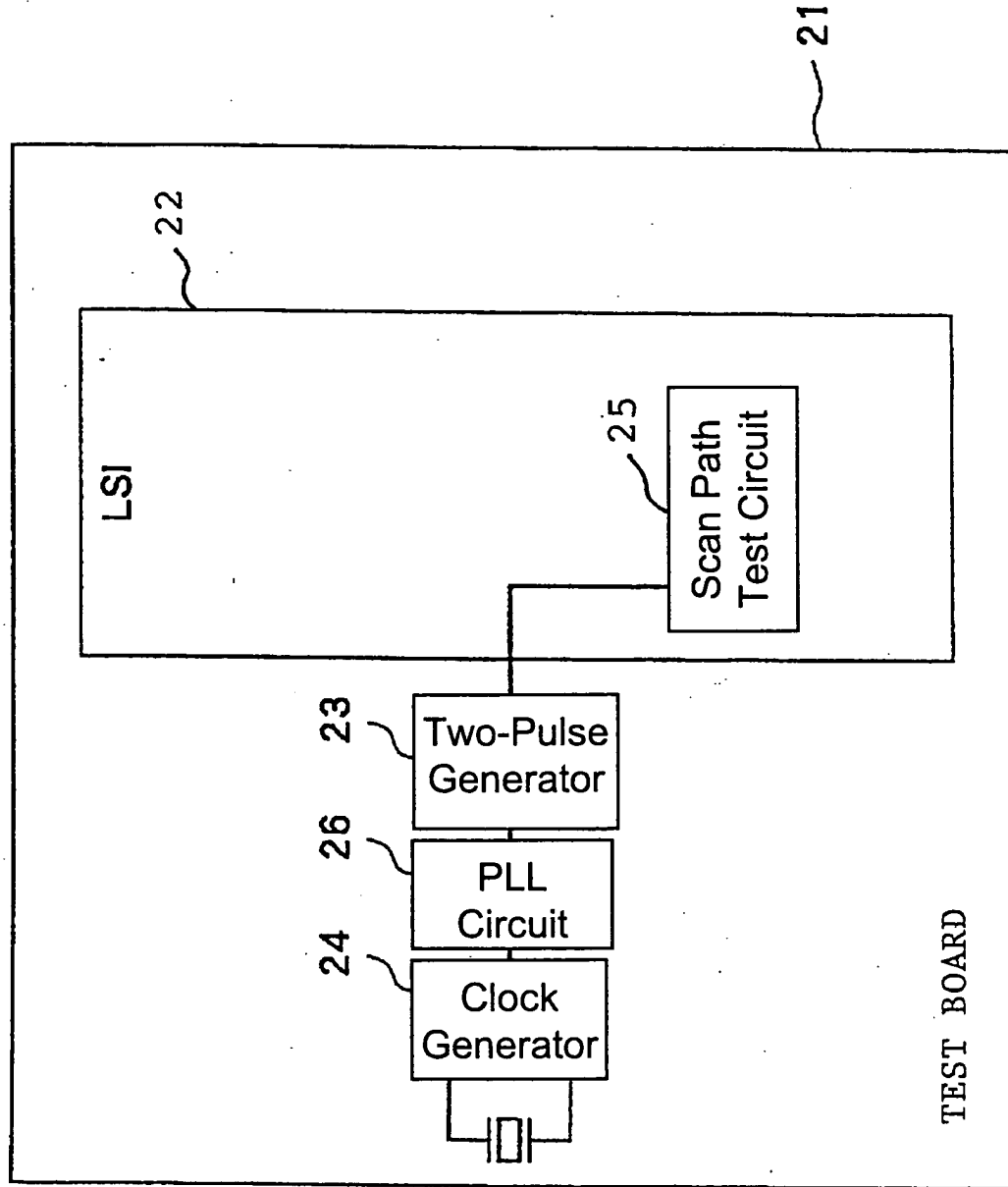


FIG. 7

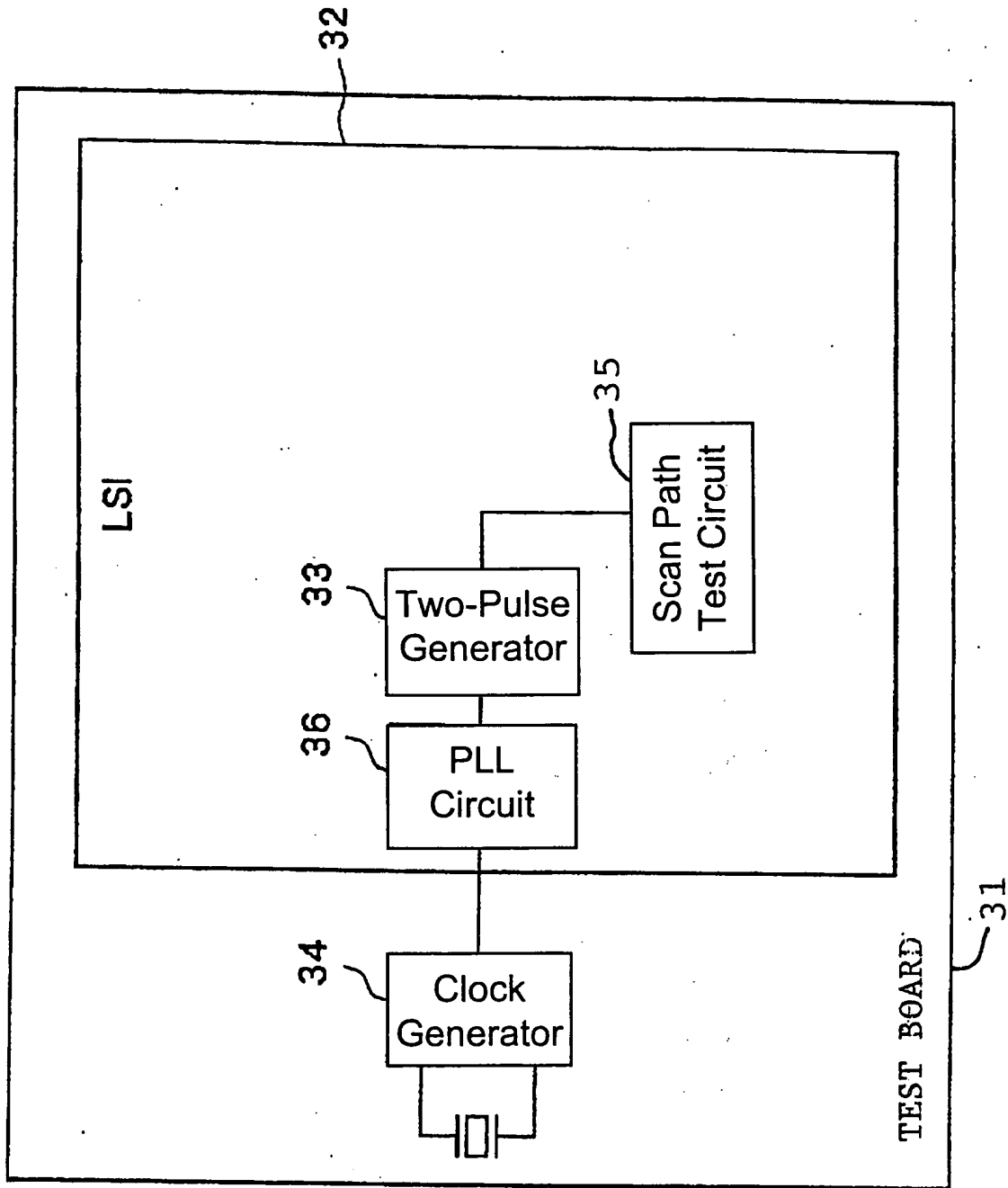


FIG. 8

